



Specification of Automotive MLCC

- Supplier : Samsung electro-mechanics
- Product : Multi-layer Ceramic Capacitor
- Samsung P/N :
- CL21B222KB65PNC
- Description : CAP, 2.2nF, 50V, ±10%, X7R, 0805
- AEC-Q 200 Specified

A. Samsung Part Number

		<u>(</u>	<u>CL</u>	<u>21</u>	<u>B</u>	<u>222</u>	<u>K</u>	<u>B</u>	<u>6</u>	<u>5</u>	<u>P</u>	<u>N</u>	<u>c</u>
			1	2	3	4	5	6	1	8	9	10	1
1	Series	Samsung Multi-layer Ceramic Capacitor											
2	Size	0805 (in	ch cc	ode)		L:	2.0) ± 0.1	mm			W:	1.25 ± 0.1 mm
(3)	Dielectric	X7R					(8)	Inne	r elec	trode			Ni , Open mode
4	Capacitance	2.2 nF					Ŭ	Term	ninatio	on			Cu , Ag-epoxy
5	Capacitance	±10 %						Plati	ng				Sn 100% (Pb Free)
	tolerance						9	Prod	uct				Automotive
6	Rated Voltage	50 V					10	Grad	le coc	le			Standard
\bigcirc	Thickness	0.6 ± 0).1	mm			1	Pack	aging)			Cardboard Type, 7" reel

B. Reliablility Test and Judgement condition

	Performance	Test condition				
High Temperature	Appearance : No abnormal exterior appearance Unpowered, 1000hrs@T=150°C					
Exposure	Capacitance Change : Within ±10%	Measurement at 24±2hrs after test conclusion				
	Tan δ: 0.03 max					
	IR : More than 10,000 Ω or 500 $\Omega \times \mu F$					
	Whichever is Smaller					
Temperature Cycling	Appearance : No abnormal exterior appearance	1000Cycles				
	Capacitance Change : Within ±10%	Measurement at 24±2hrs after test conclusion				
	Tan δ: 0.03 max	1 cycle condition :				
	IR : More than 10,000 Ω or 500 $\Omega \times \mu F$	-55+0/-3℃(15±3min) -> Room Temp(1min.)				
	Whichever is Smaller	-> 125+3/-0℃(15±3min) -> Room Temp(1min.)				
Destructive Physical	No Defects or abnormalities	Per EIA 469				
Analysis						
Moisture Resistance	Appearance : No abnormal exterior appearance	10Cycles, t=24hrs/cycle				
	Capacitance Change : Within ±12.5%	Heat (25~65 $^\circ C$) and humidity (80~98%), Unpowered				
	Tan δ: 0.03 max	measurement at 24±2hrs after test conclusion				
	IR : More than 10,000 $\mbox{M}\Omega$ or 500 $\mbox{M}\Omega \times \mu F$					
	Whichever is Smaller					
Humidity Bias	Appearance : No abnormal exterior appearance	1000hrs 85 $^{\circ}$ C/85%RH, Rated Voltate and 1.3~1.5V,				
	Capacitance Change : Within ±12.5%	Add 100kohm resistor				
	Tan δ: 0.035 max	Measurement at 24±2hrs after test conclusion				
	IR : More than 500MΩ or 25 MΩ× μ F	The charge/discharge current is less than 50mA.				
	Whichever is Smaller					
High Temperature	Appearance : No abnormal exterior appearance	1000hrs @ TA=125℃, 200% Rated Voltage,				
Operating Life	Capacitance Change : Within ±12.5%	Measurement at 24±2hrs after test conclusion				
	Tan δ: 0.035 max	The charge/discharge current is less than 50mA.				
	IR : More than 1000№ or 50№×µF					
	Whichever is Smaller					

	Performance	Test condition					
External Visual	No abnormal exterior appearance	Microscope (`10)					
Physical Dimensions	Within the specified dimensions	Using The calipers					
Mechanical Shock	Appearance : No abnormal exterior appearance	Three shocks in each direction should be applied along					
Mechanical Shock	Capacitance Change : Within ±10%	3 mutually perpendicular axes of the test specimen (18 shocks)					
	Tan δ , IR : initial spec.	Peakvalue Duration Wave Velocity					
		1,500G 0.5ms Half sine 4.7m/sec.					
Vibration	Appearance : No abnormal exterior appearance	5g's for 20min., 12cycles each of 3 orientations,					
	Capacitance Change : Within ±10%	Use 8"×5" PCB 0.031" Thick 7 secure points on one long side					
	Tan δ, IR : initial spec.	and 2 secure points at corners of opposite sides. Parts mounted					
		within 2" from any secure point. Test from $10\sim 2000 \text{Hz}$.					
Resistance to	Appearance : No abnormal exterior appearance	Solder pot : 260±5°C, 10±1sec.					
Solder Heat	Capacitance Change : Within ±10%						
	Tan δ, IR : initial spec.						
Thermal Shock	Appearance : No abnormal exterior appearance	-55℃/+125℃.					
Thermal onock	Capacitance Change : Within ±10%	Note: Number of cycles required-300,					
	Tan δ , IR : initial spec.	Maximum transfer time-20 sec, Dwell time-15min. Air-Air					
ESD	Appearance : No abnormal exterior appearance	AEC-Q200-002					
	Capacitance Change : Within ±10%						
	Tan δ, IR : initial spec.						
Solderability	95% of the terminations is to be soldered	a) Preheat at 155℃ for 4 hours, Immerse in solder for 5s at 245±5℃					
	evenly and continuously	b) Steam aging for 8 hours, Immerse in solder for 5s at 245±5℃					
		c) Steam aging for 8 hours, Immerse in solder for 120s at 260±5°C					
		solder : a solution ethanol and rosin					
Electrical	Capacitance : Within specified tolerance	The Capacitance /D.F. should be measured at 25℃,					
Characterization	Tan δ (DF): 0.025 max.	1⊮z±10%, 1.0±0.2Vrms					
	IR(25℃) : More than 10,000№ or 500№× <i>μ</i> F	I.R. should be measured with a DC voltage not exceeding					
	IR(125 °C) : More than1,000№ or 10№× μ F	Rated Voltage @25℃, @125℃ for 60~120 sec.					
	Whichever is Smaller						
	Dielectric Strength	Dielectric Strength : 250% of the rated voltage for 1~5 seconds					
Board Flex	Appearance : No abnormal exterior appearance	Bending to the limit (2mm) for 5 seconds					
	Capacitance Change : Within ±10%						
Terminal	Appearance : No abnormal exterior appearance	18N, for 60±1 sec.					
Strength(SMD)	Capacitance Change : Within ±10%						
,							
Beam Load	Destruction value should not be exceed	Beam speed					
	Chip Length < 2.5mm	0.5±0.05mm/sec					
	a) Chip Thickness > 0.5㎜ : 20N						
	b) Chip Thickness \leq 0.5mm : 8N						
Temperature	X7R						
Characterisitcs	(From -55℃ to 125℃, Capacitance change sho	ud be within ±15%)					

C. Recommended Soldering method :

Reflow (Reflow Peak Temperature : 260+0/-5 $^\circ$, 10sec. Max) Meet IPC/JEDEC J-STD-020 D Standard

* For the more detail Specification, Please refer to the Samsung MLCC catalogue.